TDSW020A2T

Product Specification November 11, 2021



TDSW020A2T Functional Diagram

dc – 20 GHz Absorptive GaAs SPDT

Switch Features

Frequency Range: dc – 20 GHz
Low Insertion Loss: 3 dB(Max)

Isolation: >40 dB

• Input & Output Return Loss: > 15 dB

• Input P1dB: 28 dBm

• Die Size: 1.5 mm × 1.5 mm × 0.1 mm

• Package*: 5 mm x 5 mm Hermetic Ceramic QFN

Typical Applications

- Radar
- Military & Space
- Instrumentation

CNTRL +5v = -5v

Description

The Teledyne TDSW020A2T is a wide band, absorptive, single pole, double throw (SPDT) Switch covering dc to 20 GHz. The switch features insertion loss of 3 dB(max) and greater than 40 dB Isolation up to 20 GHz. The input power for 1dB compression is 28 dBm typical. The switch operates on +5V/-5V supplies with minimal dc power consumption and is controlled using TTL-compatible voltage levels. The die is fabricated using a robust 0.15 µm InGaAs pHEMT technology. The switch will be available in both space screened die form and an alternative 5 mm x 5 mm hermetic sealed QFN package* with space level screening.

Figure 1

Absolute Maximum Ratings¹

Parameter	Absolute Maximum	Units
RF Input Power	35	dBm
Control Voltage ON State OFF State	-0.5 to +5.5 +6 -6	V V V
Operating temperature	-40 to +85	°C
Storage Temperature	-65 to +150	°C

Note:

1. Operation beyond these limits may cause permanent damage to the component.

* Package preview: Contact factory for availability.



Electrical Specifications for Bare Die @ T_A = 25 °C, Z_O = 50 $\Omega^{3,4,5}$

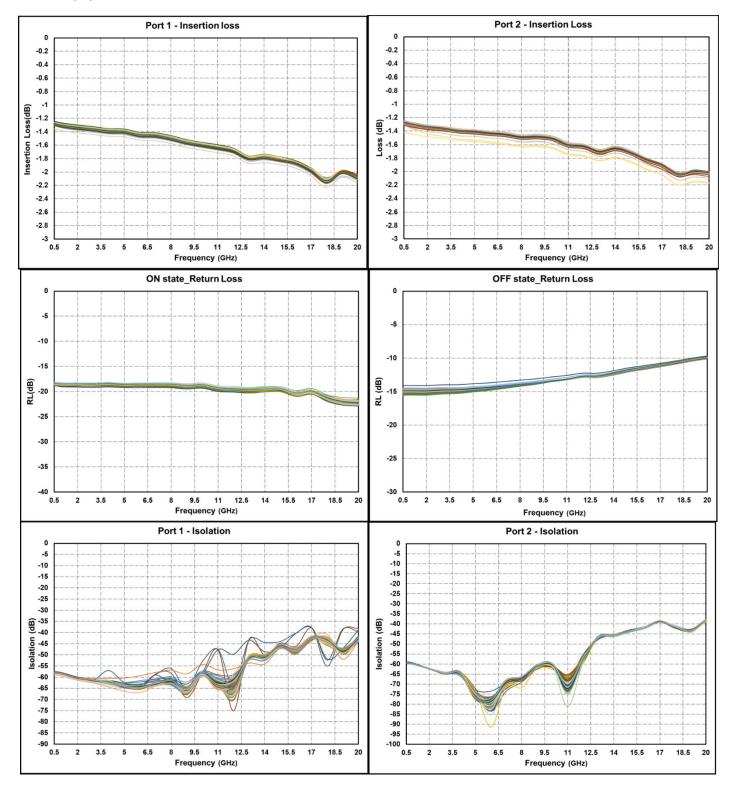
Parameter	Minimum	Typical	Maximum	Units
Frequency Range	dc		20.0	GHz
Insertion Loss		2.2	3.0	dB
Input Return Loss		-17	-15	dB
Output Return Loss		-17	-15	dB
Off State Return Loss		-15	-10	dB
Isolation	-37	-40		dB
Input P1dB		28		dBm
+5 V Supply Voltage (V _{DD})	4.5	5.0	5.5	V
-5 V Supply Voltage (Vss)	-5.5	-5.0	-4.5	V
+5 V Supply Current (IDD)		0.86	1.5	mA
-5 V Supply Current (Iss)	-0.5	-0.11		mA
CNTRL V _{IH}	0.7 x V _{DD}	5	5.5	V
CNTRL V _{IL}	-0.5	0	0.3xV _{DD}	V

Notes:

- 3. The RF input & output ports are dc coupled.
- 4. For reliable operation external dc blocking capacitors are required at the RF input & output ports
- 5. Bare/unpackaged die only. Contact factory for information about packaged die product

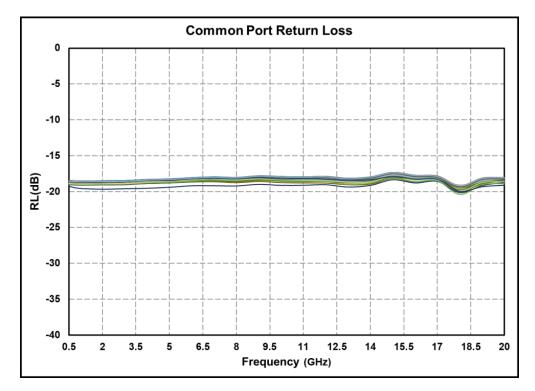


One Wafer Bare Die Probed Data @ T_A = 25 °C, Zo = 50 Ω , 255 random die from one wafer

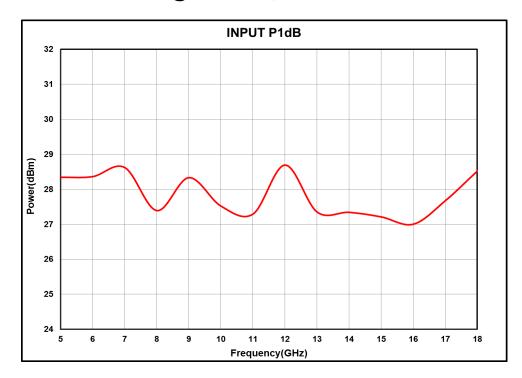




One Wafer Bare Die Probed Data @ T_{A} = 25 $^{\rm o}C,$ Zo = 50 $\Omega,$ 255 random die from one wafer



Test Fixture Data Bare Die @ T_A = 25 °C, Zo = 50 Ω

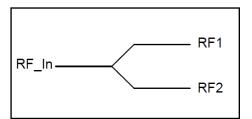




Truth Table

Control Voltage

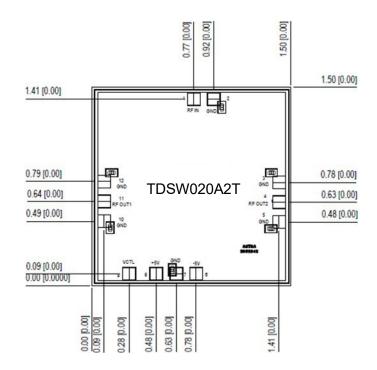
State	Bias condition	
Low "0"	0 to 0.5 V	
High "1"	3.3 V to 5.0 V	



Ctrl_vol	RF_In to RF1	RF_In to RF2
0(Low)	Off	On
1(High)	On	Off



RF and dc Pad Details



Units : millimeters (inches)

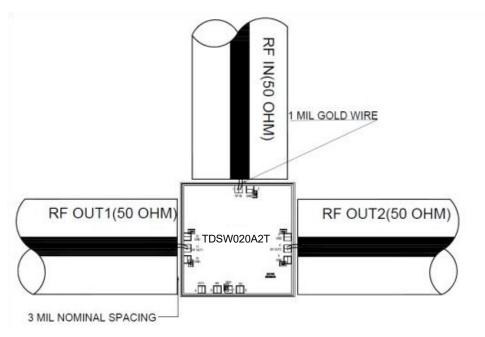
Notes:

1. All RF bond pads are 110 μ m x 110 μ m and dc bond pads are 100 μ m x 100 μ m

2. Pad no. 1 : RF IN Pad no. 2,3,5,7,10,12 3. : GND 4. Pad no. 11 : RF OUT1 5. Pad no.6 : -5 V 6. Pad no.8 : +5 V Pad no.9 7. : Vctrl 8. Pad no.4 : RFOUT2



Recommended Die Assembly Diagram



Notes:

- 1. Two 1 mil (0.0254 mm) bond wires of minimum length should be used for RF input, RF output.
- 2. Input and output 50-ohm lines are preferably on 5 mil or 10 mil RT Duroid substrate.
- 3. The RF input & output ports are dc decoupled on-chip.
- 4. Coefficient of thermal expansion matching is recommended for reliability purpose.
- 5. Use high thermal conductive material for die mounting for long term reliability.
- 6. Maintain base plate temperature less than 70⁰C under RF operation for optimum performance.

Die attach: For Epoxy attachment, use of a two-component conductive epoxy is recommended. An epoxy fillet should be visible around the total die periphery. If Eutectic attachment is preferred, use of flux less AuSn (80/20) 1 - 2 mil thick preform solder is recommended. Use of AuGe preform should be strictly avoided.

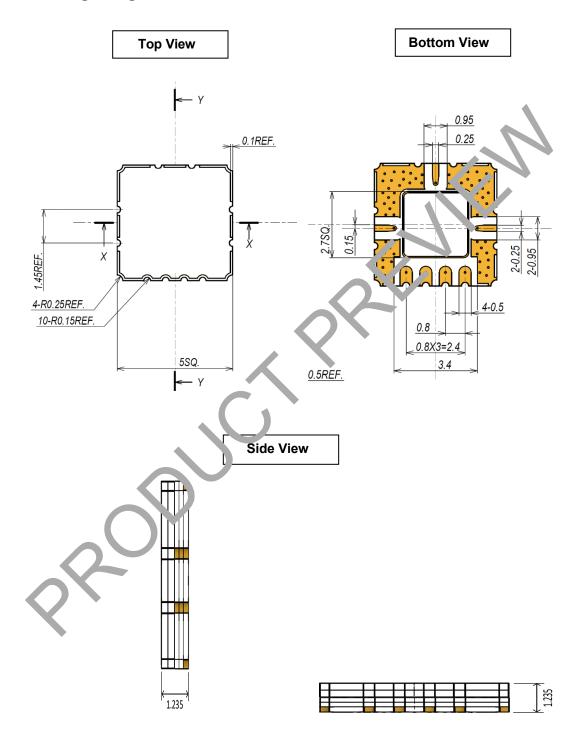
Wire bonding: For dc pad connections use either ball or wedge bonds. For best RF performance, use of $150 - 200 \, \mu m$ length of wedge bonds is advised. Single Ball bonds of $250 - 300 \, \mu m$ though acceptable, may cause a deviation in RF performance.



GaAs MMIC devices are susceptible to Electrostatic discharge. Proper precautions should be observed during handling, assembly & testing



CQFN Package Diagram*



^{*}Package preview: Contact factory for availability. Information on packaged product is subject to change without prior notification.



Part Number Ordering Details

The TDSW020A2T RF Switch is available in the following die and 5 mm x 5 mm ceramic QFN* configurations.

Part Number	Description	Packaging	Notes
TDSW020A2T-98	EM DIE	Gel-Pack	
TDSW020A2T-99	FM DIE	Gel-Pack	w/ Method 2010 space visual
TDSW020A2T-00	EVK	Module	EVK for packaged device
TDSW020A2T-01*	EM Flight Unit	CQFN*	25 °C testing only
TDSW020A2T-11*	FM Flight Unit	CQFN*	Contact factory for space screening options

^{*}Contact factory for availability. Information on packaged product is subject to change without prior notification.



Document Revision History

Document No.	Description	Date
TDSW020A2T_Rev 1 11_11_2021	Initial Release	11/11/2021

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